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Synthesis and microwave dielectric properties of Ca₃SnSi₂O₉ ceramics

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1. Introduction

Microwave dielectric ceramics have been widely used in passive component [1,2], local area network and intelligent transport systems. Microwave ceramic materials include Al₂O₃ [3], silicate [4,5], MAl₂O₄ (M=Mg, Zn), Mg₄Nb₂O₉ system. Al₂O₃ has a strong raw material and processing sensitivity. MAl₂O₄ needs a high sintering temperature of 1550-1650°C [6]. Addition of TiO₂ into the spinel ZnAl₂O₄ improved its properties and the τ_f approached zero for 0.83 ZnAl₂O₄-0.17 TiO₂. This temperature compensated composition has excellent microwave dielectric properties (ε_r = 12.67, Q_u = 9950 at 10.075 GHz) [7]. For x = 0.25 in $(1 - x)MgAl_2O_4 - xTiO_2$, the microwave quality factor reaches a maximum value of $Q \times f$ = 105,400 GHz at 7.5 GHz, where ε_r = 11.035 and $\tau_f = -12 \text{ ppm}/^{\circ}\text{C}$ [8]. Magnesium niobate has a low Q value $(Q \times f = 26,069 \text{ GHz})$ [9]. The microwave dielectric properties of Mg₄Nb₂O₉ + 3 wt.% LiF sintered at 850 °C for 10 h were: ε_r = 12.6, $Q \times f$ = 103,607 GHz, τ_f = -70.5 ppm/°C [10].

Silicates, such as magnesium silicate (MgSiO₃), forsterite (Mg₂SiO₄), zinc silicate (Zn₂SiO₄) and wollastonite (CaSiO₃) have low dielectric constant and high quality factor. MgSiO₃ ceramics have excellent dielectric properties: $\varepsilon_r = 6.7$, $Q \times f = 121,200$ GHz, $\tau_f = -17$ ppm/°C [11], however, they are easy to be powdered due to the inevitable phase transformation. The microwave properties of Mg₂SiO₄ ceramics containing 0.5 wt.% LMZBS glass were: $\varepsilon_r = 7.3$, $Q \times f = 121,200$ GHz [12]. (Mg_{0.4}Zn_{0.6})₂SiO₄ ceramics indicate a good combination of microwave dielectric characteristics:

ABSTRACT

Ca₃SnSi₂O₉ ceramics were synthesized and their microwave dielectric properties were investigated. Non-stoichiometric compositions (molar ratio of Ca:Sn:Si = 1:1.2:1) were employed to synthesize pure monoclinic Ca₃SnSi₂O₉ phase when sintering temperature varied between 1400 and 1525 °C. The Ca₃Sn_xSi₂O_{9+δ} (*x* = 1.2) ceramics sintered at 1500 °C exhibited microwave dielectric properties: a dielectric constant (ε_r) of 8.44, a quality factor ($Q \times f$) of 92,000 GHz and a temperature coefficient of resonant frequency (τ_f) of -60 ppm/°C. Monoclinic Ca₃SnSi₂O₉ phase ceramics have a wide sintering temperature region, excellent sintering behavior and high quality factor. They are promising candidate materials for millimeter-wave devices.

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 $ε_r$ = 6.6, Q×f=95,650 GHz, and $τ_f$ = -60 ppm/°C [13]. Mg₂SiO₄ ceramics have a strong processing sensitivity [4,14]. Zn₂SiO₄ ceramics with excellent properties were synthesized by a cold isostatic pressing (CIP) at a pressure of 200–300 MPa [15–18]; however, its quality factor was low (Q×f=15,000 GHz) when the conventional solid-state method was employed [18]. CaSiO₃ ceramics have a low sintering temperature (1320 °C) and low dielectric constant (6.69); however, the low densification and porous microstructure of CaSiO₃ led to a low quality factor (Q×f=25,398 GHz) [19]. Ternary silicates contain Li₂MgSiO₄ and Sr₂ZnSi₂O₇. Li₂MgSiO₄ mixed with 1 wt.% LBS sintered at 925 °C/2 h had $ε_r$ = 5.5 and tan δ = 7 × 10⁻⁵ at 8 GHz [20]. Excellent dielectric properties ($ε_r$ = 8.4, Q×f=105,000 GHz (at 12.628 GHz) and $τ_f$ = -51.5 ppm/°C were obtained for the composition Sr₂ZnSi₂O₇ when sintered at 1475 °C/2 h [21,22].

For microwave ceramic capacitors, the low dielectric constant and high quality factor were helpful for the high self-resonant frequency (SRF) and low dielectric loss of component because of the low parasitic inductance and low insertion loss. Low dielectric constant would reduce the relaxation time and enhance the signal propagation speed when microwave ceramics were supplied in multilayer packaging system. The simple synthesis process and stable dielectric properties of ceramics were also important problems. Therefore, it is an urgent task to find a new silicate material system for microwave/millimeter-wave application.

Even though various studies were conducted on silicates, dielectric properties of monoclinic $Ca_3SnSi_2O_9$ materials were seldom investigated. In the present work, we reported the synthesis, characterization, and microwave dielectric properties of $Ca_3SnSi_2O_9$ ceramics.

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Fig. 1. XRD patterns of $Ca_3Sn_xSi_2O_{9+\delta}$ ceramic materials with various compositions at 1400 °C.

2. Experimental

Ca₃SnSi₂O₉ microwave ceramics were synthesized by the conventional solidstate method. CaCO₃, nano-SnO₂ particles (d_{50} = 0.2 µm by laser size distribution analyzer, Aladdin, Shanghai, China) and nano-SiO₂ (7 nm, Degussa, Auckland, New Zealand) were mixed with a proper molar ratio, and then milled with zirconia balls for 4 h on a planetary milling machine (QM-3SP2, Zhenguang, Nanjing, China). The mixtures were dried, and then calcined at 1100 °C for 2 h. The calcined ceramic powders were re-milled for 4 h, dried, then granulated with paraffin binder, and final pressed into cylindrical disks of 8 mm diameter and 3 mm thickness under 10 MPa pressure isostatically with a hydrostatic press (KSTY70, Haixiang, Changzhou, China). The samples were sintered at 1300–1525 °C for 4 h in air with a high temperature electric furnace (SSJ-1600, Shenjia kiln, Luoyang, China).

The crystalline phases of specimen were analyzed by X-ray diffraction (XRD) (D8 ADVANCE, Bruker, Germany) with Cu K α radiation of 2θ from 10 to 80°. The microstructure observations of the ceramic surfaces were performed under a scanning electron microscope (SEM) (LEO 1530 VP, Zeiss, Vertrieb Deutschland, Germany). The bulk density of ceramics was measured by the Archimedes method. Microwave dielectric constants (ε_r) and the quality factor values ($Q \times f$) at microwave frequencies were measured by Hakki-Coleman dielectric resonator method using a Network Analyzer (N5230 PNA-L, Agilent, Santa Clara, CA, USA). Temperature coefficient of resonant frequency (τ_f) was also measured by the same method with a changing temperature from 25 to 75°C, and calculated by the following Eq. (1):

$$\tau_f = \frac{f_{75} - f_{25}}{f_{25} \times 50} \times 10^6 \text{ (ppm/°C)}$$
(1)

where f_{75} and f_{25} represent the resonant frequency at 75 °C and 25 °C, respectively.

3. Results and discussion

3.1. Phase identification of $Ca_3Sn_xSi_2O_{9+\delta}$ ceramics

Fig. 1 shows the XRD patterns of $Ca_3Sn_xSi_2O_{9+\delta}$ (x=0.8-1.4) ceramics sintered at 1400 °C with different amounts of SnO₂. According to the XRD patterns, monoclinic $Ca_3SnSi_2O_9$ phase (JCPDS no. 46-0812) was the main crystal phase at x=0.8-1.1, accompanied with small amount of monoclinic Ca_3SiO_5 (JCPDS no. 49-0442). The Ca_3SiO_5 diffraction peaks disappeared and a pure monoclinic Ca_3SiO_5 phase appeared at x=1.2; however, trace monoclinic Ca_3SiO_5 phase appeared at x=1.3-1.4. Monoclinic $Ca_3SnSi_2O_9$ has a monoclinic structure with space group P21/c (14), and lattice parameters of a=0.7327 nm, b=1.0067 nm, and c=1.0432 nm.

Fig. 2 shows the XRD patterns of Ca₃Sn_xSi₂O_{9+ δ} (*x* = 1.2) ceramics sintered at different sintering temperatures (*T*_s). According to the XRD patterns, monoclinic Ca₃SnSi₂O₉ phase was the main crystal phase at *T*_s = 1300–1350 °C, accompanied with a small amount of tetragonal Ca₂SiO₄ (JCPDS no. 39-0298). The pure monoclinic Ca₃SnSi₂O₉ phase could be obtained when the sintering



Fig. 2. XRD patterns of $Ca_3Sn_xSi_2O_{9+\delta}$ (x = 1.2) ceramic materials sintered at various temperatures.

temperature was above 1400 °C. In this work, non-stoichiometric compositions (molar ratio of Ca:Sn:Si = 1:1.2:2) were employed to synthesize pure monoclinic Ca₃SnSi₂O₉ phase ceramics, which has a very wide sintering region (about 125 °C). The possible reason for the excessive SnO₂ was the strong evaporation of SnO₂ at high temperature [23,24].

3.2. SEM studies

The microstructures of Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) ceramics sintered at various temperatures were investigated using SEM, as shown in Fig. 3. For the specimen sintered at 1400–1450 °C, a porous microstructure was developed with a large number of pores and the no clear crystal grains could be observed. The densification and grain size increased as the sintering temperature increased. When the temperature was 1500 °C, the grain size of the specimen increased to 5 µm, and the dense microstructure was developed (see Fig. 3(3)). The uniform large grain microstructures and clear grain boundaries could be observed. When the sintering temperature was 1525 °C, Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) ceramics began to melt. Abnormal grain growth occurred and porous microstructure appeared, as exhibited in Fig. 3(4).

3.3. Microwave dielectric properties

Fig. 4 shows the relative density, dielectric constant (ε_r), quality factor ($Q \times f$) and τ_f values of the Ca₃Sn_xSi₂O_{9+ $\delta}$} (x=1.2) ceramics sintered at various temperatures for 4 h, respectively. The relative density for the specimen sintered at 1300 °C was low (63%), then increased markedly with increasing sintering temperature to a maximum value of 96.2% of the theoretical density for the specimen sintered at 1500 °C (see Fig. 4(1)). The ε_r value was low (4.93) for the specimen sintered at 1300 °C, probably due to the porous microstructure. Dielectric constant of ceramics increased with increasing sintering temperature to a maximum value of 8.44 for the specimen sintered at 1500 °C, then decreased to 7.74 at 1525 °C (see Fig. 4(2)) because of the decreased relative density (89% of the theoretical density). The dielectric constant could be evaluated by the well-known mixing rule [15].

The Q × f value of the Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) ceramics sintered at 1300 °C lower to 12,000 GHz (at 16.6 GHz) due to the low density and porous microstructure. However, it increased considerably with increasing sintering temperature, to a value of 92,000 GHz (at 15.1 GHz) for the specimens sintered at 1500 °C, then decreased as the sintering temperature was 1525 °C, as exhibited in Fig. 4(3).



Fig. 3. SEM photographs of $Ca_3Sn_xSi_2O_{9+\delta}$ (x = 1.2) ceramic materials sintered at: (1) 1400 °C, (2) 1450 °C, (3) 1500 °C, (4) 1525 °C.

The XRD results revealed the development of inhomogeneous phases consisting of monoclinic $Ca_3SnSi_2O_9$ ceramics (major phase) and Ca_2SiO_4 (minor phase) when the sintering temperature was less than 1400 °C. As the temperature increased, the pure monoclinic $Ca_3SnSi_2O_9$ phase appeared, and the densification

of specimens increased. Generally speaking, high densification, homogeneous phases and uniform grain microstructure led to a high $Q \times f$ value due to less extrinsic loss; however, the second phase and abnormal grain growth produced a low $Q \times f$ value. Therefore, the decreased $Q \times f$ value of specimen sintered at



Fig. 4. (1) Relative density and (2) ε_r , (3) $Q \times f$, and (4) τ_f values of the Ca₃Sn_xSi₂O_{9+ $\delta}$ (x = 1.2) ceramics sintered at various temperatures.}

1525 °C may have related to the low densification, abnormal grain growth and porous microstructure derivate from the melting of Ca₃Sn_xSi₂O_{9+δ} (*x* = 1.2) ceramics. The τ_f values of the Ca₃Sn_xSi₂O_{9+δ} (*x* = 1.2) ceramics sintered at various temperatures are also shown in Fig. 4(4). The τ_f values of pure monoclinic Ca₃SnSi₂O₉ phase varied between -50 and -60 ppm/°C.

Even though the $Q \times f$ value of the Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) ceramics was slightly lower than that for MgSiO₃ [10], Mg₂SiO₄ [13] or Zn₂SiO₄ [14] ceramics, it was higher than that of CaSiO₃ ceramics [18]. The τ_f value of Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) is high and immediate application in millimeter wave communication is limited; however, it may be possible to lower the τ_f value by adding suitable additives such as TiO₂ or CaTiO₃. In this work, we synthesized pure monoclinic Ca₃SnSi₂O₉ phase ceramics using the conventional solid-state method. Ca₃SnSi₂O₉ ceramics have a wide sintering temperature region (1400–1525 °C), excellent sintering behavior and high quality factor ($Q \times f$ =92,000 GHz at 15.1 GHz).

4. Conclusions

Monoclinic Ca₃SnSi₂O₉ phase ceramics were synthesized with the conventional solid-state method. The crystal phase evolution, sintering behavior and microwave dielectric properties of $Ca_3Sn_xSi_2O_{9+\delta}$ (x=0.8–1.4) ceramics were investigated. Pure monoclinic Ca₃SnSi₂O₉ phase ceramics could be synthesized at 1400-1525 °C when non-stoichiometric compositions (molar ratio of Ca:Sn:Si = 1:1.2:1) were employed. As temperature increased to 1525 °C, Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) ceramics began to melt and porous microstructure appeared. The relative density, second phase and microstructures have large influences on microwave dielectric properties of Ca₃Sn_xSi₂O_{9+ δ} (x = 1.2) ceramics. The Ca₃Sn_xSi₂O_{9+ δ} (x=1.2) ceramics sintered at 1500 °C exhibited the following microwave dielectric properties: $\varepsilon_r = 8.44$, $Q \times f = 92,000$ GHz (at 15.1 GHz) and $\tau_f = -60 \text{ ppm}/^{\circ}\text{C}$. Monoclinic Ca₃SnSi₂O₉ phase ceramics have a wide sintering temperature region and high quality factor. They could be considered as promising candidate materials for millimeter-wave devices.

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